



Low Voltage CMOS Logic – 54LVC2G66

Dual SPST Bilateral Analog Switch in bare die form

Rev 1.0
29/06/19

Description

The 54LVC2G66 Dual Single-Pole Single-Throw Analog Switch is produced using an optimised low voltage CMOS process. Each switch consists of two input/output pins and an active HIGH enable input pin (OE). A LOW signal on the enable pin (OE) turns the analog switch off. Schmitt trigger action on the enable inputs provides circuit tolerance for slow input rise and fall times. Both analog and digital signals are supported in both directions across the full V_{CC} range. The device is suited for multiplexing in analog-to-digital or digital-to-analog conversion and also finds use in signal gating, chopping or modulation/de-modulation applications.

Ordering Information

The following part suffixes apply:

- No suffix - MIL-STD-883 /2010B Visual Inspection
- "H" - MIL-STD-883 /2010B Visual Inspection + MIL-PRF-38534 Class H LAT
- "K" - MIL-STD-883 /2010A Visual Inspection (Space) + MIL-PRF-38534 Class K LAT

LAT = Lot Acceptance Test.

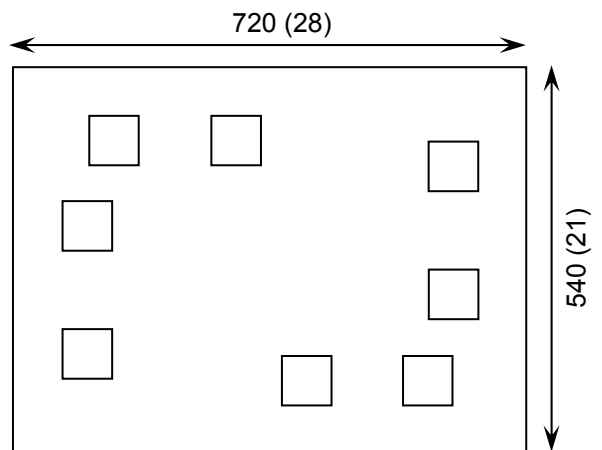
For further information on LAT process flows see below.

www.siliconsupplies.com/quality/bare-die-lot-qualification

Features:

- Wide supply voltage: V_{CC} 1.65V - 5.5V
- Very low r_{ON} : 6Ω Typ, V_{CC} = 4.5V
- High speed: t_{pd} 0.8ns Max, V_{CC} = 3.3V
- Switch current capability: 32mA
- TTL input compatibility (V_{CC} = 3.3V)
- Enable inputs accept up to 5.5V
- Rail-to-Rail Input / Output
- High noise immunity
- Tiny Die size.

Die Dimensions in μm (mils)



Supply Formats:

- Default – Die in Waffle Pack (400 per tray capacity)
- Sawn Wafer on Tape – On request
- Unsawn Wafer – On request
- Die Thickness <> 280 μm (11 Mils) – On request
- Assembled into Ceramic Package – On request

Mechanical Specification

Die Size (Unsawn)	720 x 540 28 x 21	μm mils
Minimum Bond Pad Size	70 x 70 2.76 x 2.76	μm mils
Die Thickness	280 (± 20) 11.02 (± 0.79)	μm mils
Top Metal Composition	Al-Si-Cu 3 μm	
Back Metal Composition	N/A – Bare Si	

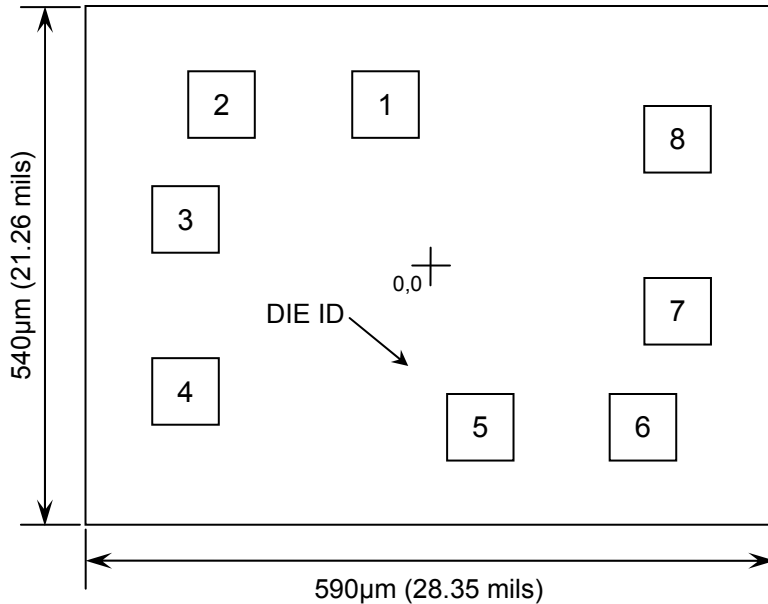




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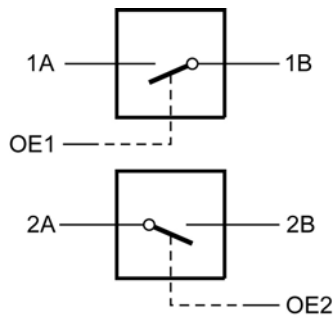
Pad Layout and Functions



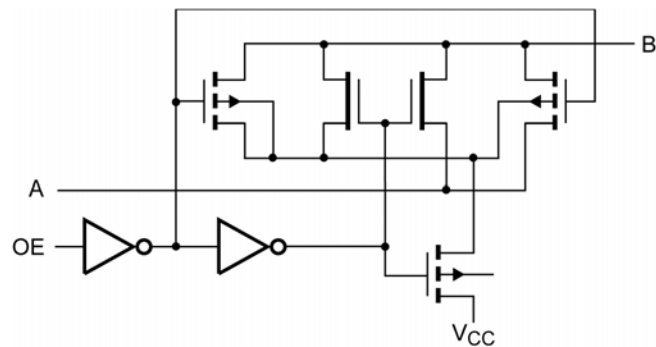
PAD	FUNCTION	COORDINATES (µm)	
		X	Y
1	2B	-47.6	166.7
2	OE1	-217.6	166.7
3	V _{CC}	-256.7	47
4	1A	-256.7	-131
5	1B	47.6	-166.7
6	OE2	217.6	-166.7
7	GND	256.4	-47
8	2A	256.7	131

CONNECT CHIP BACK TO V_{CC} OR FLOAT

Logic Diagram



Expanded Logic Diagram (x1 Switch)



Function Table

OE	SWITCH
H	ON
L	OFF

H = High level (steady state)
L = Low level (steady state)





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Absolute Maximum Ratings²

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage (Referenced to GND)	V_{CC}	-0.5 to +6.5	V
Input Voltage (Referenced to GND)	V_{IN}	-0.5 to +6.5	V
Input Clamp Current	I_{IK}	-50	mA
Switch I/O Voltage (Referenced to GND)	V_{SW}	-0.5 to $V_{CC} + 0.5$	V
On-State Switch Current	I_{SW}	± 50	mA
Switch Clamping Current	I_{SK}	± 50	mA
V_{CC} or GND Current	I_{CC}	± 100	mA
Power Dissipation in Still Air ³	P_D	250	mW
Storage Temperature Range	T_{STG}	-65 to 150	$^{\circ}C$

2. Operation above the absolute maximum rating may cause device failure. Operation at the absolute maximum ratings, for extended periods, may reduce device reliability. 3. Measured in plastic TSSOP package, results in die form are dependent on die attach and assembly method.

Recommended Operating Conditions⁴ (Voltages referenced to GND)

PARAMETER	SYMBOL	MIN	MAX	UNITS	
Supply Voltage	V_{CC}	1.65	5.5	V	
Switch I/O Voltage	V_{SW}	0	5.5	V	
High-Level Input Voltage, Enable Input	V_{IH}	$V_{CC} = 1.65V$ to $1.95V$	$0.65 \times V_{CC}$	-	V
		$V_{CC} = 2.3V$ to $2.7V$	$0.7 \times V_{CC}$	-	
		$V_{CC} = 3V$ to $3.6V$	$0.7 \times V_{CC}$	-	
		$V_{CC} = 4.5V$ to $5.5V$	$0.7 \times V_{CC}$	-	
Low-Level Input Voltage, Enable Input	V_{IL}	$V_{CC} = 1.65V$ to $1.95V$	-	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3V$ to $2.7V$	-	$0.3 \times V_{CC}$	
		$V_{CC} = 3V$ to $3.6V$	-	$0.3 \times V_{CC}$	
		$V_{CC} = 4.5V$ to $5.5V$	-	$0.3 \times V_{CC}$	
Enable Input Voltage	V_{IN}	0	5.5	V	
Operating Temperature Range	T_J	-55	+125	$^{\circ}C$	
Input Transition Rise & Fall Rate	$\Delta t / \Delta V$	$V_{CC} = 1.65V$ to $1.95V$	0	20	ns/V
		$V_{CC} = 2.3V$ to $2.7V$	0	20	
		$V_{CC} = 3V$ to $3.6V$	0	10	
		$V_{CC} = 4.5V$ to $5.5V$	0	10	

4. This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V_{IN} and V_{OUT} should be constrained to the range $GND \leq (V_{IN} \text{ or } V_{OUT}) \leq V_{CC}$. Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.





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DC Electrical Characteristics (Voltages Referenced to GND)

PARAMETER	SYMBOL	V _{CC}	CONDITIONS	LIMITS			UNITS
				25°C	85°C	FULL RANGE ⁶	
Maximum High-Level Input Voltage	V _{IH}	1.65 - 1.95V		0.65xV _{CC}	0.65xV _{CC}	0.65xV _{CC}	V
		2.3 - 2.7V		0.7xV _{CC}	0.7xV _{CC}	0.7xV _{CC}	
		2.7 - 3.6V		0.7xV _{CC}	0.7xV _{CC}	0.7xV _{CC}	
		4.5 - 5.5V		0.7xV _{CC}	0.7xV _{CC}	0.7xV _{CC}	
Maximum Low-Level Input Voltage	V _{IL}	1.65 - 1.95V		0.35xV _{CC}	0.35xV _{CC}	0.35xV _{CC}	V
		2.3 - 2.7V		0.3xV _{CC}	0.3xV _{CC}	0.3xV _{CC}	
		2.7 - 3.6V		0.3xV _{CC}	0.3xV _{CC}	0.3xV _{CC}	
		4.5 - 5.5V		0.3xV _{CC}	0.3xV _{CC}	0.3xV _{CC}	
On-State Switch Resistance ⁵	r _{ON}	1.65V	V _{IN} =V _{CC} or GND, I _{SW} = 4mA, OE = V _{IH}	12.5	30	45	Ω
		2.3V	V _{IN} =V _{CC} or GND, I _{SW} = 8mA, OE = V _{IH}	9	20	30	
		3V	V _{IN} =V _{CC} or GND, I _{SW} =24mA, OE = V _{IH}	7.5	15	23	
		4.5V	V _{IN} =V _{CC} or GND, I _{SW} =32mA, OE = V _{IH}	6	10	15	
Peak On-State Resistance ⁵	r _{ON(P)}	1.65V	V _{IN} =V _{CC} to GND, I _{SW} = 4mA, OE = V _{IH}	85	130	195	Ω
		2.3V	V _{IN} =V _{CC} to GND, I _{SW} = 8mA, OE = V _{IH}	22	30	45	
		3V	V _{IN} =V _{CC} to GND, I _{SW} =24mA, OE = V _{IH}	12	20	30	
		4.5V	V _{IN} =V _{CC} to GND, I _{SW} =32mA, OE = V _{IH}	7.5	15	23	
On-State Resistance difference between Switches	Δr _{ON}	1.65V	V _{IN} =V _{CC} to GND, I _{SW} = 4mA, OE = V _{IH}	7	7	7	Ω
		2.3V	V _{IN} =V _{CC} to GND, I _{SW} = 8mA, OE = V _{IH}	5	5	5	
		3V	V _{IN} =V _{CC} to GND, I _{SW} =24mA, OE = V _{IH}	3	3	3	
		4.5V	V _{IN} =V _{CC} to GND, I _{SW} =32mA, OE = V _{IH}	2	2	2	

5. 25°C values specified as Typical 6. -55°C ≤ T_J ≤ +125°C





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DC Electrical Characteristics Continued (Voltages Referenced to GND)

PARAMETER	SYMBOL	V _{CC}	CONDITIONS	LIMITS			UNITS
				25°C	85°C	FULL RANGE ⁶	
Off-State Switch Leakage Current	I _{SW(OFF)}	5.5V	V _{IN} = V _{CC} V _{OUT} = GND, V _{IN} = GND V _{OUT} = V _{CC} , OE = V _{IL}	±0.1	±0.2	±1	µA
On-State Switch Leakage Current	I _{SW(ON)}	5.5V	V _{IN} = V _{CC} or GND, OE = V _{IH} , V _{OUT} = Open	±0.1	±1	±2	µA
Enable Input Current	I _{IN}	5.5V	OE = V _{CC} or GND,	±0.1	±1	±1	µA
Supply Current	I _{CC}	5.5V	V _{SW} = V _{CC} or GND	1	1	4	µA
Additional Supply Current	ΔI _{CC}	5.5V	One input at V _{CC} - 0.6V, other inputs GND or V _{CC}	500	500	500	µA
Enable Input Capacitance	C _{IN}	5V		TYPICAL			pF
				3.5			
Switch Input/Output Capacitance	C _{IO(OFF)}	5V		6			
	C _{IO(ON)}			14			
Power Dissipation Capacitance	C _{PD}	1.8V	f = 10MHz, T _A = 25°C	8			pF
		2.5V		9			
		3.3V		9.5			
		5V		11			

AC Electrical Characteristics⁷

PARAMETER	SYMBOL	V _{CC}	CONDITIONS	LIMITS			UNITS
				25°C	85°C	FULL RANGE ⁵	
Propagation Delay, Input A or B to Output B or A ⁸	t _{PLH} /t _{PHL} (t _{pd})	1.8 ±0.15V	C _L = 30pF, R _L = 1kΩ	2	2	3	ns
		2.5 ±0.2V	C _L = 30pF, R _L = 500Ω	1.2	1.2	2	ns
		3.3 ±0.3V	C _L = 50pF, R _L = 500Ω	0.8	0.8	1.5	ns
		5 ±0.5V	C _L = 50pF, R _L = 500Ω	0.6	0.6	1	ns

7. Not production tested in die form, characterized by chip design and tested in package 8. The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).





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AC Electrical Characteristics Continued⁷

PARAMETER	SYMBOL	V _{CC}	CONDITIONS	LIMITS			UNITS
				25°C	85°C	FULL RANGE ⁵	
Propagation Delay, Enable to Output A or B	t _{PZL} / t _{PZH} (t _{en})	1.8 ±0.15V	C _L = 30pF, R _L = 1kΩ,	10	10	13	ns
		2.5 ±0.2V	C _L = 30pF, R _L = 500Ω,	5.6	5.6	7.5	
		3.3 ±0.3V	C _L = 50pF, R _L = 500Ω,	4.4	4.4	6	
		5 ±0.5V	C _L = 50pF, R _L = 500Ω,	3.9	3.9	5	
Propagation Delay, Disable to Output A or B	t _{PLZ} / t _{PZH} (t _{dis})	1.8 ±0.15V	C _L = 30pF, R _L = 1kΩ,	10.5	10.5	11.5	ns
		2.5 ±0.2V	C _L = 30pF, R _L = 500Ω,	6.9	6.9	8.5	
		3.3 ±0.3V	C _L = 50pF, R _L = 500Ω,	7.2	7.2	8	
		5 ±0.5V	C _L = 50pF, R _L = 500Ω,	6.3	6.3	6.5	

Analog Switching Characteristics⁷ (T_A = 25°C)

PARAMETER	SYMBOL	V _{CC}	CONDITIONS	LIMITS			UNITS
				MIN	TYPICAL	MAX	
Frequency Response (Switch On), Input A or B to Output A or B	f _{MAX}	1.65V	C _L = 50pF, R _L = 600Ω, f _{IN} = sine wave	-	35	-	MHz
		2.3V		-	120	-	
		3V		-	175	-	
		4.5V		-	195	-	
		1.65V	C _L = 5pF, R _L = 50Ω, f _{IN} = sine wave	-	>300	-	
		2.3V		-	>300	-	
		3V		-	>300	-	
		4.5V		-	>300	-	
Crosstalk between Switches ⁸ , Input A or B to Output A or B	V _{CT}	1.65V	C _L = 50pF, R _L = 600Ω, f _{IN} = 1MHz sine wave	-	-58	-	dB
		2.3V		-	-58	-	
		3V		-	-58	-	
		4.5V		-	-58	-	
		1.65V	C _L = 5pF, R _L = 50Ω, f _{IN} = 1MHz sine wave	-	-42	-	
		2.3V		-	-42	-	
		3V		-	-42	-	
		4.5V		-	-42	-	

8. Adjust f_{in} voltage to obtain 0 dBm at input





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Analog Switching Characteristics continued⁷ (T_A = 25°C)

PARAMETER	SYMBOL	V _{CC}	CONDITIONS	LIMITS			UNITS	
				MIN	TYPICAL	MAX		
Crosstalk between Digital Inputs and Switch, OE to A or B	V _{CT}	1.65V	C _L = 50pF, R _L = 600Ω, f _{IN} = 1MHz square wave	-	35	-	dB	
		2.3V		-	50	-		
		3V		-	70	-		
		4.5V		-	100	-		
Feed-through attenuation (Switch Off), Input A or B to Output A or B	α _{off(FT)}	1.65V	C _L = 50pF, R _L = 600Ω, f _{IN} = 1MHz sine wave	-	-58	-	dB	
		2.3V		-	-58	-		
		3V		-	-58	-		
		4.5V		-	-58	-		
			1.65V	C _L = 5pF, R _L = 50Ω, f _{IN} = 1MHz sine wave	-	-42	-	dB
			2.3V		-	-42	-	
			3V		-	-42	-	
			4.5V		-	-42	-	
Sine-Wave Distortion, Input A or B to Output A or B	THD	1.65V	C _L = 50pF, R _L = 10kΩ, f _{IN} = 1KHz sine wave	-	0.100	-	%	
		2.3V		-	0.025	-		
		3V		-	0.015	-		
		4.5V		-	0.010	-		
			1.65V	C _L = 50pF, R _L = 10kΩ, f _{IN} = 10KHz sine wave	-	0.150	-	%
			2.3V		-	0.025	-	
			3V		-	0.015	-	
			4.5V		-	0.010	-	

Switching Waveforms

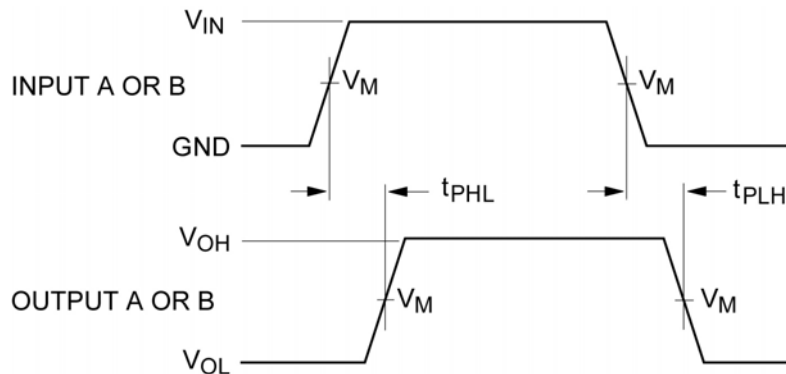


Figure 1 – Propagation Delay Input to Output





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Switching Waveforms continued

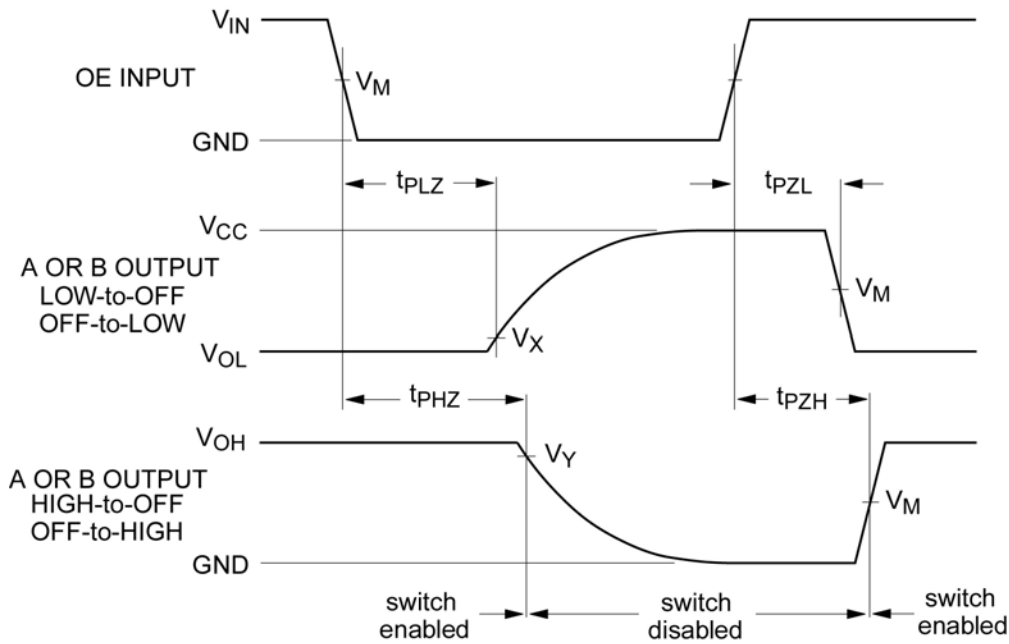


Figure 2 – Enable & Disable Timing, Switch

FIGURE 1 & 2 MEASUREMENT POINTS									
Supply V_{CC}	Input		V_M	V_{EXT}			V_X	V_Y	
	V_{IN}	t_r / t_f		t_{PZL}, t_{PLZ}	t_{PZH}, t_{PHZ}	t_{PHL}, t_{PLH}			
$1.8 \pm 0.15V$	V_{CC}	$\leq 2 \text{ ns}$	$0.5xV_{CC}$	$2xV_{CC}$	GND	open	$V_{OL} + 0.15V$	$V_{OH} - 0.15V$	
$2.5 \pm 0.2V$	V_{CC}	$\leq 2 \text{ ns}$	$0.5xV_{CC}$	$2xV_{CC}$	GND	open	$V_{OL} + 0.15V$	$V_{OH} - 0.15V$	
$3.3 \pm 0.3V$	V_{CC}	$\leq 2.5 \text{ ns}$	$0.5xV_{CC}$	$2xV_{CC}$	GND	open	$V_{OL} + 0.3V$	$V_{OH} - 0.3V$	
$5 \pm 0.5V$	V_{CC}	$\leq 2.5 \text{ ns}$	$0.5xV_{CC}$	$2xV_{CC}$	GND	open	$V_{OL} + 0.3V$	$V_{OH} - 0.3V$	





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Test Circuit

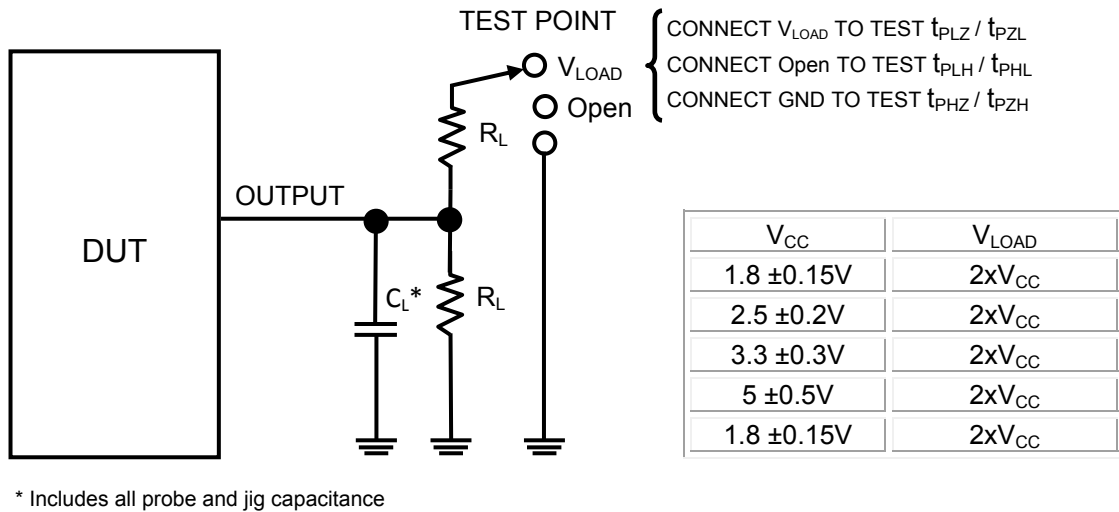


Figure 3 – Test Setup

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